

INFORMATION DISCLOSURE STATEMENT BY APPLICANT Sheet 1 of 2

Docket No. B0004/7080

Applicant:

Serial No:

Filed:

For:

Jochen Franzen
09/778,654
February 7, 2001
GRIDLESS TIME-OF-FLIGHT MASS SPECTROMETER FOR ORTHOGONAL

ION INJECTION

Examiner:

Not Yet Assigned

Art Unit:

2881

U.S. PATENT DOCUMENTS					
Exam Inits	Cite No.	Patent Number	Kind Code	Patentee or Applicant Name	Issue Date
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Examiner Signature	cm. El-Shammaa	Date Considered	11.26.02
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INFORMATION DISCLOSURE STATEMENT BY APPLICANT Sheet 2 of 2	Docket No. B0004/7080
Applicant: Jochen Franzen Se Janno: E 09/778,654 Filed: Grebruary 7, 2001 For: 1 1000 GRIDLESS TIME-OF-FLIGHT MASS SPECTION Examiner: Not Yet Assigned Art Trityrant 2881	CTROMETER FOR ORTHOGONAL

AIT CHARAINE 2001						
	07	THER PRIOR ART – NON PATENT LITERA	ATURE AND I	DOCUMENTS		
Exam Inits	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the a (book, magazine, journal, serial, symposium, catalog, etc.), date city and/or country where published.			Т	
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Examiner Signature		M. El. Shammaa	Date Considered	11.26.02		